

**Notice of References Cited**

Application/Control No.

10/002,576

Applicant(s)/Patent Under  
Reexamination  
CHUN ET AL.

Examiner

Harry D Wilkins, III

Art Unit

1742

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,202,710 A	05-1980	Naito et al	148/233
	B	US-4,461,655 A	07-1984	Kerridge	148/227
	C	US-5,869,195 A	02-1999	Ramanarayanan et al	428/610
	D	US-6,287,393 B1	09-2001	Garg et al	148/206
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 02-185960 A	07-1990	Japan	Kawato et al	C23C 4/00
	O	JP 03-044414 A	02-1991	Japan	Suzuki et al	C21D 8/00
	P	JP 04-337024 A	11-1992	Japan	Murai	C22C 38/40
	Q	JP 05-059427 A	03-1993	Japan	Murai	C23C 8/22
	R	JP 05-059527 A	03-1993	Japan	Murai	C23C 8/22
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.